

Amendments to the Claims:

1. (Currently Amended) A method for testing a plurality of circuits of an active matrix organic light emitting display (AMOLED) ~~prior to implantation of organic light emitting diodes (OLED)~~, the AMOLED comprising a write scan line configured to enable a circuit to be tested responsive to a selection signal and a data line configured to transmit a data signal to the circuit, the circuit comprising a first transistor and a second transistor respectively comprising a source, a gate and a drain, the source or the drain of the first transistor is connected to the data line, the gate of the first transistor is connected to the write scan line, the drain or the source of the second transistor being a test output terminal and been directly connected to a signal extractor, the method comprising the following steps ~~prior to implantation of organic light emitting diodes (OLED)~~:

assigning a value of the data signal to the write scan line;

assigning a value of the selection signal to the data line; and

extracting a signal from the test output terminal.

2. (Original) The method of claim 1, wherein the step of assigning a value of the data signal is to assign a voltage value within a range of 7V ~ 10V, and the step of extracting a signal is to extract a current signal.

3. (Original) The method of claim 2, wherein the normal functionality of the circuit is concluded if the current signal is between 20 μ A ~ 0.002 μ A.

4. (Currently Amended) A system for testing a plurality of circuits of an AMOLED ~~prior to the implantation of OLEDs~~, the AMOLED comprising a write scan line configured to enable a circuit to be tested responsive to a selection signal and a data line configured to transmit a data signal to the circuit, the circuit comprising a first transistor and a second transistor respectively comprising a source, a gate and a drain, the source or the drain of the first transistor is connected to the data line, the gate of the first transistor is connected to the write scan line, the drain or the source of the second transistor being a test output terminal and been directly connected to a signal extractor, the system comprising:

a data input device for inputting a value of the data signal prior to implantation of organic light emitting diodes (OLED);

a pixel selection device for inputting a value of the selection signal prior to implantation of organic light emitting diodes (OLED); and

a signal extractor, connected to the test output terminal, for extracting a signal prior to implantation of organic light emitting diodes (OLED).